

## **UNIT-3**

### **MOSFET CONSTRUCTION, OPERATION, CHARACTERISTICS, AC EQUIVALENT CIRCUIT, MOSFET AS AN AMPLIFIER, CMOS INVERTER, NAND GATE AND NOR GATE, BASIC PRINCIPLES AND ADVANTAGES OF NEGATIVE FEEDBACK**

#### **INTRODUCTION:**

The field effect transistor (FET) is a three terminal device used for a variety of applications similar to BJT. There are certain similarities as well as a few differences between the two types of transistors i.e, BJT and FET. The primary difference being BJT is a current controlled device whereas FET is a voltage controlled device. Just as there are npn and pnp bipolar transistors there are n-channel and p-channel field effect transistors. However BJT is bipolar device where both charge carriers electrons and holes contribute to conduction whereas FET is a unipolar device where conduction is due to either electrons or holes. FET's one of the most important characteristic is it has high input impedance. Also FETs are more temperature stable than BJTs and FETs are usually smaller than BJTs making them particularly useful in integrated circuits (IC) chips.

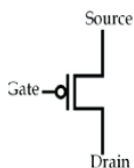
## Differences between BJT and MOSFET:

BJT	MOSFET
Current controlled device	Voltage controlled device
Bipolar	Unipolar
Less input impedance compared to MOSFET	High input impedance
Takes more area on an Integrated circuit	Less area on an Integrated circuit
More fabrication cost	Less fabrication cost
No terminals are interchangeable	Source and Drain terminals are interchangeable.
Gain is high	Gain is comparatively less
No terminals isolated	Gate terminal is isolated by $\text{SiO}_2$ layer

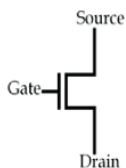
There are three types of FETs: Junction Field Effect Transistor (JFET), Metal-oxide Semiconductor Field Effect Transistor (MOSFET), and Metal Semiconductor Field Effect Transistor (MESFET).

## Symbols of MOSFET:

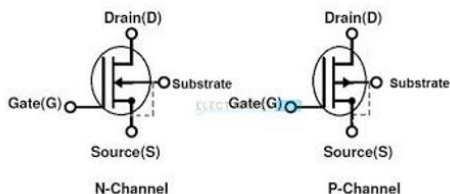
P-MOSFET



N-MOSFET



OR



## CONSTRUCTION OF MOSFET:

MOSFET has become one of the most important devices used in the design and construction of integrated circuits. Its thermal stability and other general characteristics make it extremely popular in integrated circuit design. MOSFETs are further classified into depletion type and enhancement type which define the basic mode of operation. We study only enhancement type in our syllabus.

**Enhancement type MOSFET construction:** The basic construction of the n-channel enhancement MOSFET is shown in the Figure 1. It has three terminals namely source, gate and drain. A slab of p-type material is formed from a silicon base and is referred to as substrate. This substrate may be internally connected to the source terminal or can be used as a fourth terminal to externally control its potential level. Over the substrate two n type regions are formed as shown in Figure1. These regions form source and drain terminals which are connected through metallic contacts. Over this substrate a very thin layer of silicon dioxide is formed and a metallic contact is formed which becomes the gate terminal. The silicon dioxide (insulator/dielectric) layer is present to isolate the gate metallic platform from the region between the source and the drain. The built in potential between source and gate is referred to as threshold voltage( $V_{th}$ ).

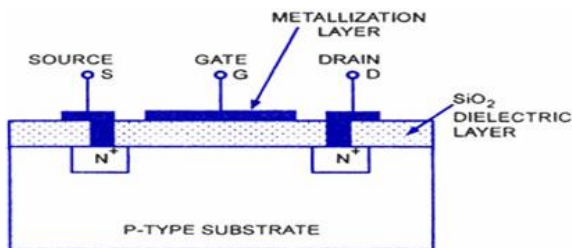


Figure 1: n- channel enhancement type MOSFET(Cross sectional view)

## BASIC OPERATION AND CHARACTERISTICS:

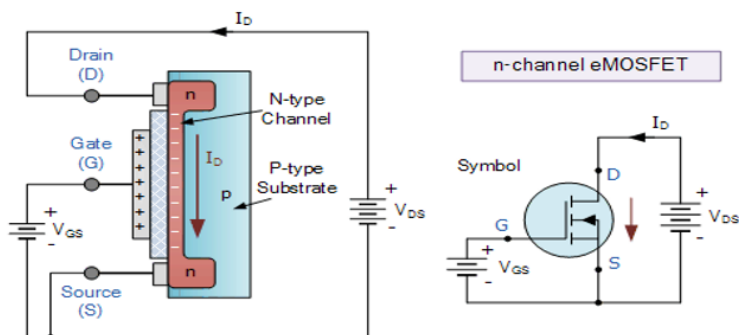


Figure 2: Bias conditions of n- channel enhancement type MOSFET

Operations of N-MOSFET are as follows:

**Case 1:  $V_{GS} < V_{th}$  and  $V_{DS} > 0$ :** With  $V_{DS}$  some positive voltage and  $V_{GS}$  at 0V, There are two reverse biased pn junctions between n doped regions and p substrate to oppose any significant current flow between drain and source. Hence current in the device is effectively nil. Hence the device is in cut-off condition.

$$\text{Eqn.1: } I_D = 0$$

Device in Cut-off:  $V_{GS} < V_{th}$

**Case 2:  $V_{GS} > V_{th}$  and  $V_{DS} < V_{GS} - V_{th}$ :** With  $V_{DS}$  and  $V_{GS}$  set at some positive voltage, the positive potential at the gate will pressure the holes in the p-substrate (majority carriers) along the edge of sio2 layer to leave the area and enter into deeper regions of the p-substrate. However the electrons in the p substrate (minority carriers) will be attracted to the positive gate and accumulate in the region near the surface of sio2 layer. The sio2 layer's insulating properties will prevent

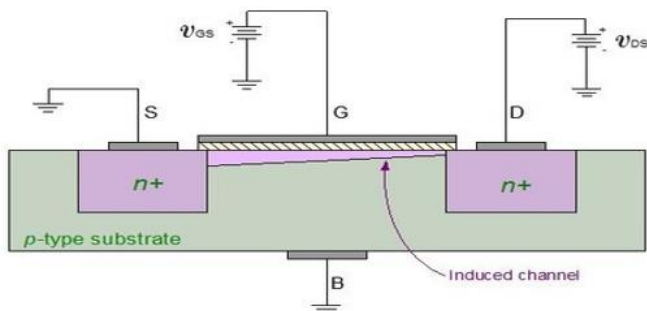
these electrons from getting absorbed at the gate terminal. As  $V_{GS}$  increases in magnitude, the concentration of electrons near the  $SiO_2$  surface increases until eventually the induced n type region can support a measurable amount of current flow between source and drain. This n type region between source and drain is called channel. The level of  $V_{GS}$  that results in formation of the channel and hence significant increase in drain current ( $I_D$ ) is called threshold voltage ( $V_{th}$ ). Figure 2 shows the formation of the channel between drain and source. Under this condition, the device will operate in linear or ohmic or triode region. Eqn.2 represents the N-MOSFET current equation in ohmic region, where K is a constant representing process parameter.

$$\text{Eqn.2: } I_D = K[(V_{GS} - V_{th})V_{DS} - V_{DS}^2 / 2]$$

Device in Linear or Ohmic:  $V_{GS} - V_{th} > V_{DS}$

Where K is the process parameter in  $A/V^2$

**Case 3:  $V_{GS} > V_{th}$  and  $V_{DS} = V_{GS} - V_{th}$ :** If  $V_{GS}$  is held constant at some voltage greater than  $V_{th}$  and increase the level of  $V_{DS}$  the drain current will eventually reach a saturation level. The levelling off of  $I_D$  is due to pinching off process as shown in the Figure 3 at the drain end of the induced channel since drain is more reverse biased than the source.



### Figure 3: Pinch off proces

Also if  $V_{GS}$  is fixed and  $V_{DS}$  is increased, according to eqn 2, the gate will become less and less positive with respect to drain and hence there is reduction in channel width. Eventually the channel will be reduced to the point of pinch-off and a saturation region is established. The saturation level of  $V_{DS}$  is related to the level of applied  $V_{GS}$  by,

$$V_{DS\text{ sat}} \geq V_{GS} - V_{th}$$

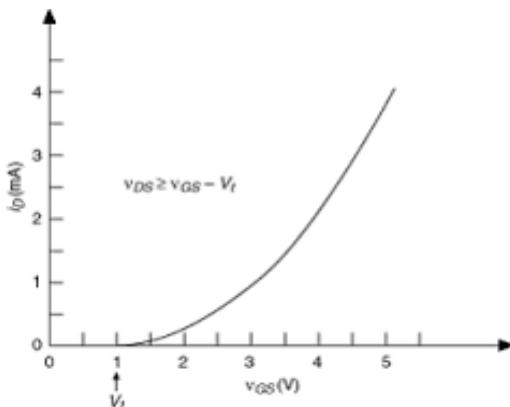
After pinch-off, further increase in  $V_{DS}$  does not cause any increase in  $I_D$  attaining saturation. The eqn 3 represents the N-MOSFET current equation in saturation region.

Eqn.3:  $I_D = K/2 \cdot (V_{GS} - V_{th})^2$

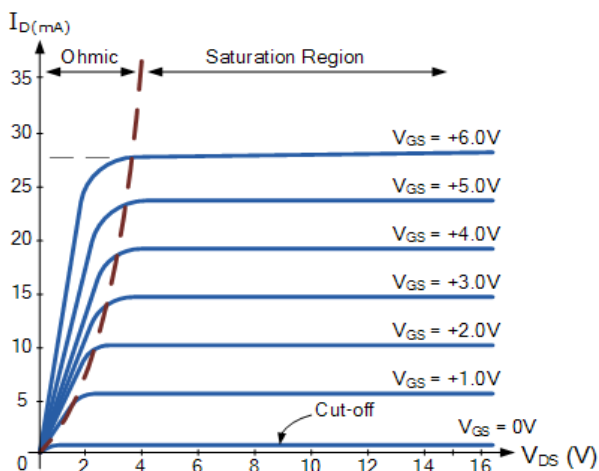
Device in Saturation:  $V_{DS} \geq V_{GS} - V_{th}$

Where  $K$  is the process parameter in  $A/V^2$

**TRANSFER CHARACTERISTICS ( $I_D$  Vs  $V_{GS}$  for a fixed  $V_{DS}$ ):**



## OUTPUT CHARACTERISTICS ( $I_D$ Vs $V_{DS}$ for a fixed $V_{GS}$ ):



**Figure 4: Drain characteristics**

As shown in the Figure 4, there are three regions in the drain characteristics of MOSFET namely ohmic /triode region where  $V_{GS} > V_{th}$  and  $I_D$  is increasing, saturation region where  $I_D$  gets saturated by increasing levels of  $V_{DS}$  and cut-off region where  $I_D$  is zero as  $V_{GS} < V_{th}$ .

## MOSFET AS AN AMPLIFIER:

The Figure 6 shows N-MOSFET in voltage divider configuration used for amplification along with the DC-load line on its input characteristics.

Note: Circuit analysis is similar to BJT.

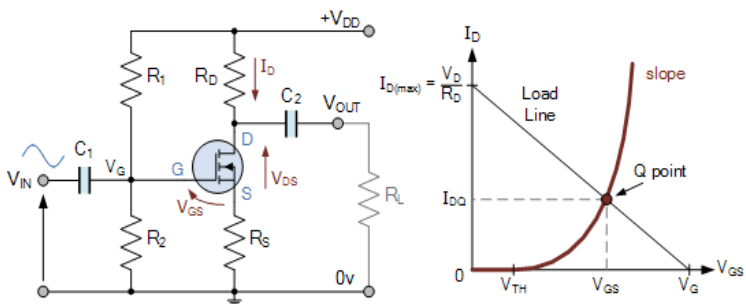


Figure 6: N-MOSFET as an amplifier

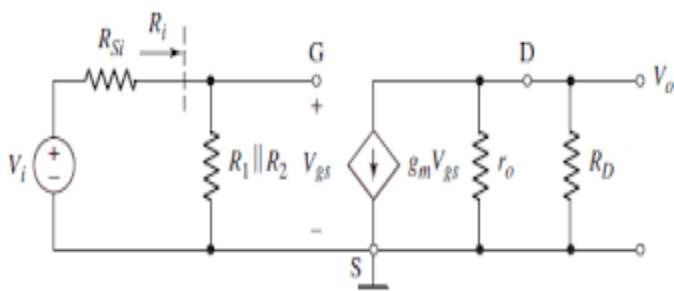


Figure 7: Small signal (AC) equivalent model of CS-amplifier

Input Impedance	$Z_i = R_1 \parallel R_2$
Output Impedance	$Z_o = r_o \parallel R_D$
Transconductance $g_m$	$K (V_{GS} - V_{th})$ or $2I_D / (V_{GS} - V_{th})$ or $\sqrt{2I_D \cdot K}$
$r_{ds}$ for small value of $V_{DS}$	$r_{ds} = 1 / K (V_{GS} - V_{th})$
Gain (without load resistance)	$A_v = -g_m \cdot R_D$
Gain (with load resistance)	$A_v = -g_m \cdot (R_D \parallel R_L)$



**CMOS inverter:** A very effective logic circuit with high input impedance, fast switching speeds, and lower operating power levels can be obtained by constructing p channel and n channel MOSFETS on a same substrate. This configuration is called complementary MOSFET arrangement. A complementary MOS (CMOS) inverter is implemented as the series connection of a p-device and an n-device, as shown in Figure 8. Note that the source and the substrate of the p - device is tied to the VDD rail, while the source and the substrate(VSS or GND) of the n-device are connected to the ground bus and drain terminals of both devices are connected to the output  $V_o$ .

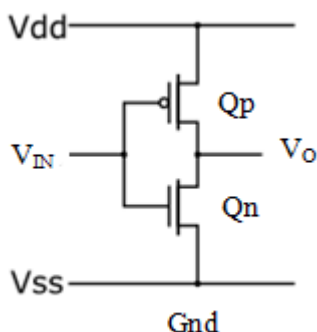


Figure 8:CMOS Inverter

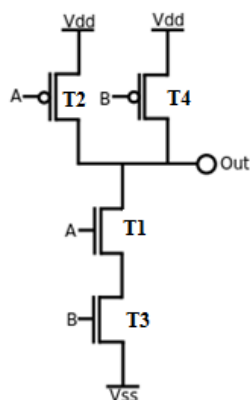
An inverter is a circuit that inverts the applied signal. That is, if the logic levels of operation are 0V and 5V, an input level of 5V will result in output level of 0V and vice versa. For logic levels defined above, application of 5V at the input  $V_{IN}$ ,  $V_{GS}$  of  $Q_n=5V$  and  $Q_n$  is on, resulting in low resistance between drain and source. Since  $V_{IN}$  and  $V_{ss}$  are at 5V,  $V_{GS}$  of  $Q_p=0V$ , and hence  $Q_p$  is off. The resulting resistance level between drain and source is quite high for  $Q_p$ . Hence  $V_o$  becomes 0V establishing inversion process. For an applied voltage  $V_{IN}$  of 0V,  $V_{GSN}=0V$  and  $Q_n$  will be off and

$V_{GSP} = -5V$ , turning on the p channel MOSFET. The result is that  $Q_p$  will present a small resistance,  $Q_n$  a high resistance level, and  $V_o = 5V$ .

$V_{IN}$	$Q_n$	$Q_p$	$V_o$
0V(Low)	OFF	ON	5V(HIGH)
5V(HIGH)	ON	OFF	0V(LOW)

## THE CMOS NAND GATE:

The schematic diagram of a 2-input CMOS NAND gate is shown in Figure.9. It can be seen that in this structure, the n-type driving transistors are connected in series while the p-type load transistors are connected in parallel. Transistors are driven in n-type cum p-type pairs with one transistor ON while the other is OFF. A table of the conducting states of the transistors for all logic combinations of the inputs is given below.



**Figure 9 CMOS NAND gate**

IN A	IN B	T <sub>1</sub>	T <sub>2</sub>	T <sub>3</sub>	T <sub>4</sub>	OUT
LO	LO	OFF	ON	OFF	ON	HI
LO	HI	OFF	ON	ON	OFF	HI
HI	LO	ON	OFF	OFF	ON	HI
HI	HI	ON	OFF	ON	OFF	LO

### THE CMOS NOR GATE:

The schematic diagram of a 2-input CMOS NOR gate is shown in Figure.10. It can be seen that similar to NAND gate structure, the n-type driving transistors are connected in parallel while the p-type load transistors are connected in Series. Transistors are a driven in n-type cum p-type pairs with one transistor ON while the other is OFF. A table of the conducting states of the transistors for all logic combinations of the inputs is given below.

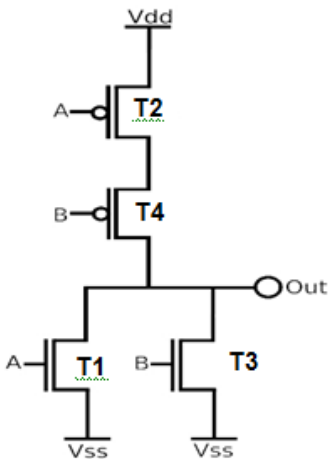


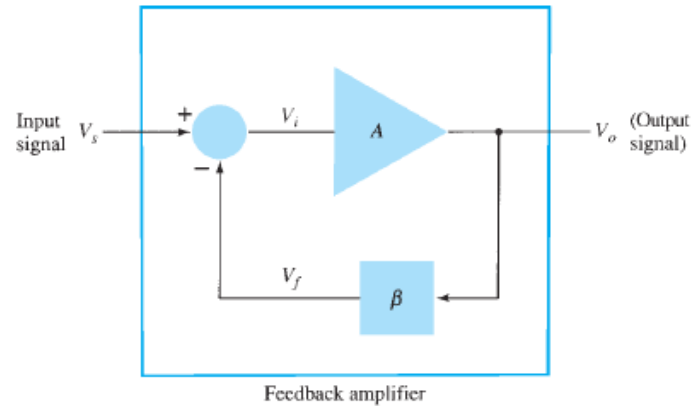
Figure 10 CMOS NOR gate

A	B	T1	T2	T3	T4	OUT
LO	LO	OFF	ON	OFF	ON	HI

LO	HI	OFF	ON	ON	OFF	LO
HI	LO	ON	OFF	OFF	ON	LO
HI	HI	ON	OFF	ON	OFF	LO

Negative Feedback

The block diagram of a feedback amplifier is shown in fig2.1.



**Fig2.1: Simple block diagram of feedback amplifier.**  
**Gain with feedback:**

$$A = \frac{V_o}{V_s} = \frac{V_o}{V_i}$$

If a feedback signal  $V_f$  is connected in series with the input, then

$$V_i = V_s - V_f$$

Since  $V_o = AV_i = A(V_s - V_f) = AV_s - AV_f = AV_s - A(\beta V_o)$

then  $(1 + \beta A)V_o = AV_s$

so that the overall voltage gain *with* feedback is

$$A_f = \frac{V_o}{V_s} = \frac{A}{1 + \beta A}$$

**Gain stability with feedback:**

$$\left| \frac{dA_f}{A_f} \right| = \frac{1}{|1 + \beta A|} \left| \frac{dA}{A} \right|$$

$$\left| \frac{dA_f}{A_f} \right| \approx \left| \frac{1}{\beta A} \right| \left| \frac{dA}{A} \right| \quad \text{for } \beta A \gg 1$$

This shows that magnitude of the relative change in gain  $\left| \frac{dA_f}{A_f} \right|$  is reduced by the factor  $|\beta A|$  compared to that without feedback  $\left( \left| \frac{dA}{A} \right| \right)$ .

**Advantages of negative feedback amplifiers:**

1. Input impedance increases by a factor of  $1 + A\beta$
2. Output impedance decreases by a factor of  $1 + A\beta$
3. Bandwidth increases by a factor of  $1 + A\beta$
4. Distortion decreases by a factor of  $1 + A\beta$
5. Noise decreases by a factor of  $1 + A\beta$
6. Stability of the gain improves by a factor of  $1 + A\beta$